

Long Pulse Duration of F₂ Laser for 157nm Lithography

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ABSTRACT

An ultra narrow line width of the F₂ laser, narrower than 0.2pm, is required for a CaF₂ only refractive optics exposure system. Also, a low peak laser power is needed for the extension of the optics lifetime. These ultra narrow line width and low peak power are achievable by long pulse duration.

We, Association of Super-Advanced Electronics Technologies (ASET), are developing an ultra line narrowed F₂ laser below 0.2pm, with 5mJ high output energy, by adopting a 2-stage F₂ laser system, which consists of an oscillator and an amplifier. The oscillator for this 2-stage system is required to have an ultra narrow line width of below 0.2pm. We have developed F₂ laser with very long laser pulse duration of over 65ns (Tis: the integral square pulse width), in a free running operation. And, by installing a line-narrowing module (LNM) in this F₂ laser, an ultra narrow line width of below 0.2 pm (FWHM, deconvolved) has been realized. This F₂ laser was successfully used for the oscillator of 2-stage system ¹⁾.

Keywords: F₂ laser, F₂ laser lithography, Long pulse duration, Ultra narrow line width, 2-stage system

1. INTRODUCTION

In ASET F₂ laser lithography technology project, we are developing an ultra line-narrowed F₂ laser for a CaF₂ only refractive optics exposure system. The specification targets of this F₂ laser are an ultra narrow line width of below 0.2 pm and high output energy of 5mJ, etc. In order to realize these targets, we are adopting a 2-stage F₂ laser system, which consists of an oscillator and an amplifier ¹⁾. For the 2-stage system, we have made an oscillator F₂ laser with a line-narrowing module (LNM) inside the laser cavity, whose line width is narrower than 0.2 pm.

In case of a line narrowed excimer laser with a LNM, the spectral line width becomes narrower, by elongating the pulse duration ²⁾. However, the long pulse duration operation with F₂ laser had been considered to be very difficult ³⁾.

It has been confirmed that a pulsed power module with a very fast rise time of the output voltage (a high speed PPM) obtains long pulse duration, because a temporal long homogeneous discharge is realized by the high speed PPM. A line narrowed ArF excimer laser for lithography with very long pulse duration of over 50 ns (Tis) has been developed by GIGAPHOTON INC, by using their high speed PPM ²⁾.

We have succeeded in achieving very long pulse duration of over 65 ns (Tis) from an oscillator F₂ laser for the 2-stage system, by using a high speed PPM supplied from GIGAPHOTON Inc, and by adopting a He-Ne mixed buffer gas. A

temporal long discharge is obtained by using the He-Ne mixed buffer gas; because discharge resistance of the He-Ne mixed buffer gas is lower than that of He only buffer gas.

An ultra narrow line width of below 0.2 pm (FWHM, deconvolved) with 0.2 mJ has been obtained, by installing a LNM in the oscillator F₂ laser. And by using this laser as the oscillator for 2-stage system, we have achieved below 0.2 pm with high output energy of 15 mJ¹⁾.

2. LONG PULSE DURATION OF F₂ LASER AND CONSIDERATION

Fig. 1 compares the laser pulse shape in free running operation of the oscillator F₂ laser with that of our old F₂ laser. In the oscillator F₂ laser, the high speed PPM from GIGAPHOTON is used whose output voltage rise time is fast, about 70 ns. The output voltage rise time of the PPM in the old F₂ laser, about 90 ns, is slower than that of the oscillator F₂ laser. For both F₂ lasers, He buffer gas was used. From Fig. 1, it is found that the laser pulse shape from the oscillator F₂ laser has 2 peaks, so that the laser pulse duration (T_{is}) is longer than that of the old one. It is considered that a temporal long homogeneous discharge is realized by the high speed PPM, consequently the longer laser pulse duration is realized in a F₂ laser, by using a high speed PPM. Fig. 2 shows the laser pulse duration of the oscillator F₂ laser with He only buffer gas and with various mixing ratio He-Ne buffer gases. By increasing Ne mixing ratio, the decay time of the laser pulse becomes slower, and longer pulse durations are obtained, from about 20ns to about 45ns. On the other hand, a peak power and output energy of the laser pulse becomes lower. As a lower discharge resistance is obtained by increasing Ne mixing ratio, the laser pulse duration is considered to become longer. Moreover, we consider that the high speed PPM realizes such a long pulse with the He-Ne mixed gas. Even though He-Ne mixed gas is used, long pulse duration is not obtained from our old F₂ laser whose voltage rise time is slow, as mentioned above.

Fig. 3 shows measured laser pulse shapes of the oscillator F₂ laser, by changing the reflectance of the laser cavity output coupler. By increasing the reflectance, the pulse duration becomes longer. The output energy, however, shows the maximum at the reflectance of about 40 %, in the oscillator F₂ laser.

3. LINE NARROWING AND CONSIDERATION

Fig. 4 and Fig.5 are a laser pulse and a spectral shape of the oscillator F₂ laser with a LNM, respectively. The LNM consists of expansion prisms and a grating. The pulse duration of 22 ns is shorter than that in free running operation. The output energy was 0.2 mJ, which is remarkably lower than output energy of 4 mJ in free running. This short duration and low output energy are due to large optical loss of the LNM. Therefore, by reducing the LNM loss, much longer pulse duration and much narrower line width will surely be obtained.

4. CONCLUSION

We have developed a F₂ laser with very long laser pulse duration of 65 ns (T_{is}). It has been confirmed that long pulse duration in a F₂ laser is achieved by using a pulsed power module with a very fast rise time of the output voltage (a high speed PPM) and using a He-Ne mixed buffer gas. And, by installing a line-narrowing module (LNM) in the F₂ laser, an

ultra-narrow line width of below 0.2 pm has been obtained. Long pulse duration is considered to realize such narrow line width. As the optical loss of the LNM is very large, much narrower line width will be achieved by reducing the LNM loss, By applying this F₂ laser with the LNM for an oscillator of 2-stage system, an ultra narrow line width of below 0.2pm with a high output energy of 15 mJ has been obtained ¹⁾.

We believe that 2-stage F₂ laser system, in which an oscillator with such long pulse duration is used, will be utilized for a CaF₂ only refractive optics exposure system.

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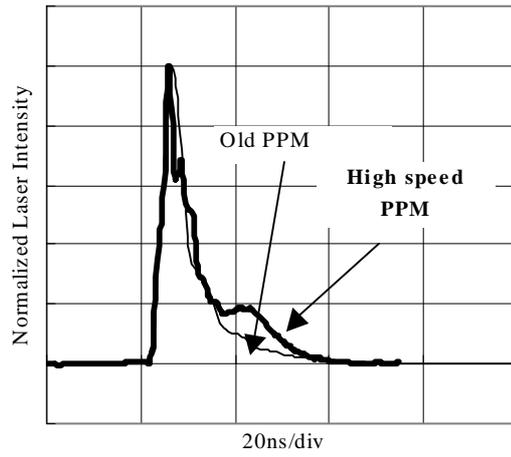


Fig.1 Laser pulse shapes with the high speed PPM and the old PPM

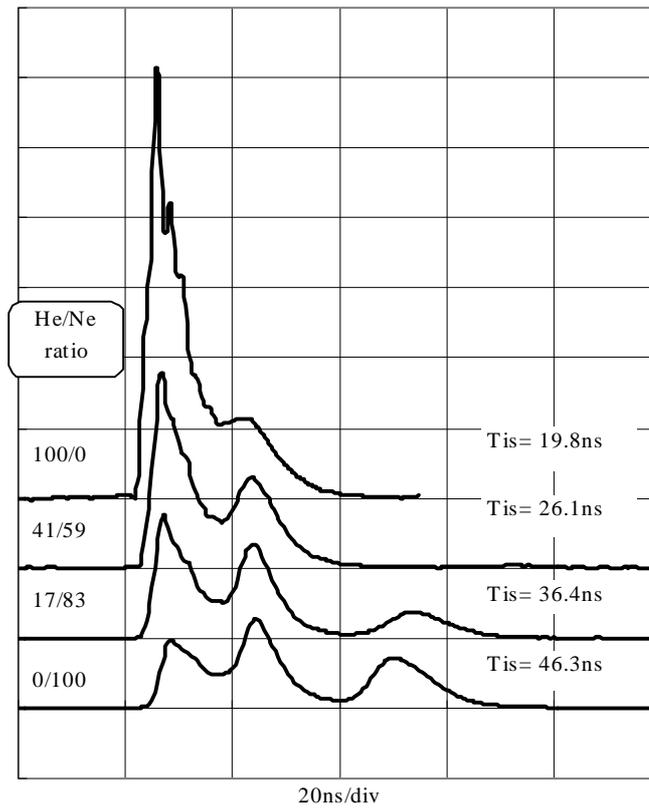


Fig. 2 Laser pulse shapes for various He-Ne mixing ratio

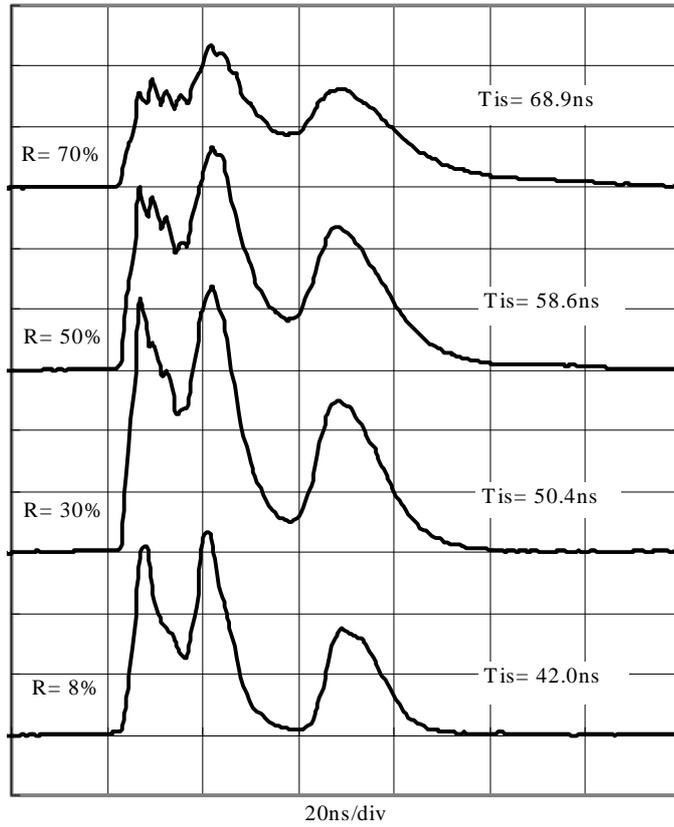


Fig. 3 Laser pulse shapes for various output couplers of laser cavity

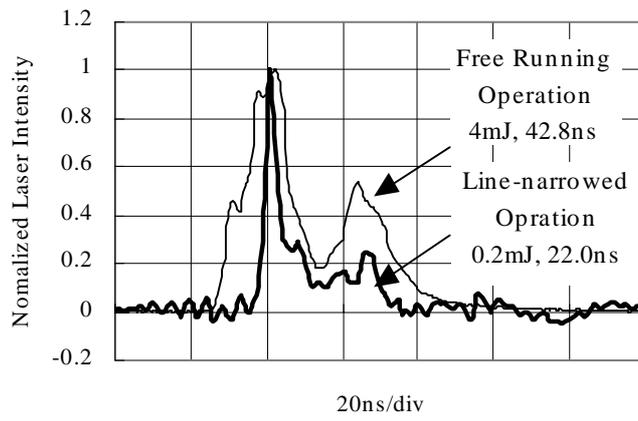


Fig. 4 Laser pulse shapes in a free running and a line narrowed operation

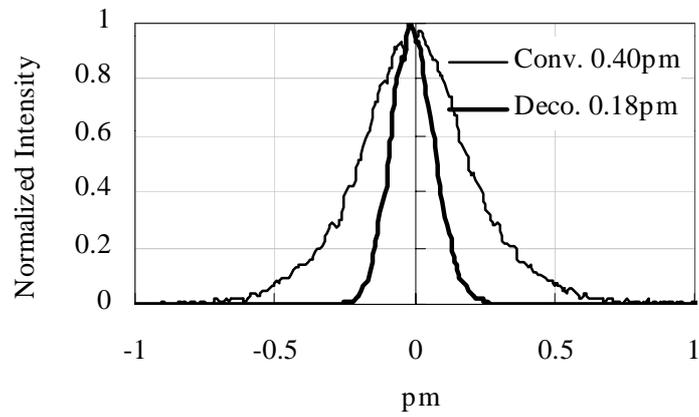


Fig. 5 Laser spectral shape in a line narrowed operation